



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill
Serial No. : 10/630,361
Filed : July 29, 2003
Title : COMPENSATION FOR ERRORS IN OFF-AXIS INTERFEROMETRIC MEASUREMENTS

Art Unit : 2877
Examiner : Unknown

MAIL STOP AMENDMENT

Commissioner for Patents
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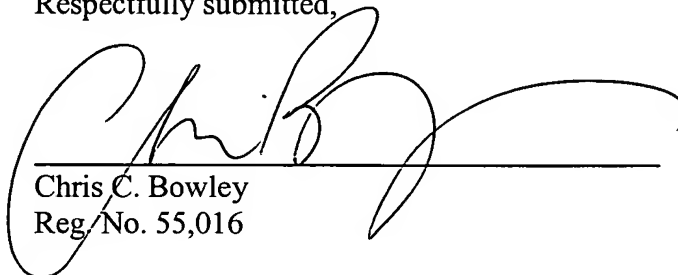
INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 7/25/2005


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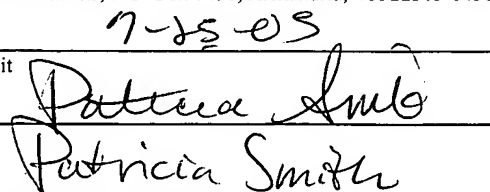
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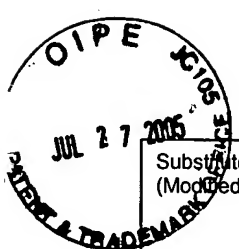
I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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7-25-05

Patricia Smith

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-331001Application No.
10/630,361**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Henry A. HillFiling Date
July 29, 2003Group Art Unit
2877**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	20050151951	7/14/2005	Hill			
	AB	20050134862	6/23/2005	Hill			
	AC	20050030549	2/10/2005	Hill			
	AD	20040189998	9/30/2004	Hill			
	AE	20040046965	3/11/2004	Hill			
	AF	20030090675	5/15/2003	Fujiwara			
	AG	20020089671	7/11/2002	Hill			
	AH	20020048026	4/25/2002	Isshiki et al.			
	AI	20010035959	11/1/2001	Hill			
	AJ	6,912,054	6/28/2005	Hill			
	AK	6,906,784	6/14/2005	Hill			
	AL	6,891,624	5/10/2005	Hill			
	AM	6,882,430	4/19/2005	Hill			
	AN	6,867,867	3/15/2005	Hill			
	AO	6,839,141	1/4/2005	Hill			
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	AQ	6,819,434	11/16/2004	Hill			
	AR	6,806,962	10/19/2004	Hill			
	AS	6,806,961	10/19/2004	Hill			
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	AU	6,791,693	9/14/2004	Hill			
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	AW	6,757,066	6/29/2004	Hill			
	AX	6,747,744	6/8/2004	Hill			
	AY	6,738,143	5/18/2004	Chu			
	AZ	6,727,992	4/27/2004	Hill			
	AAA	6,710,884	3/23/2004	Hill			

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-331001	Application No. 10/630,361
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Henry A. Hill	
		Filing Date July 29, 2003	Group Art Unit 2877

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ABB	6,700,665	3/2/2004	Hill			
	ACC	6,650,419	11/18/2003	Hill			
	ADD	6,384,899	5/7/2002	den Boef			
	AEE	6,330,105	12/11/2001	Rozelle et al.			
	AFF	6,304,318	10/16/2001	Matsumoto			
	AGG	6,285,457	9/4/2001	Ukaji			
	AHH	6,252,668	6/26/2001	Hill			
	AII	6,246,481	6/12/2001	Hill			
	AJJ	6,159,644	12/12/2000	Hidetoshi			
	AKK	6,134,007	10/17/2000	Naraki et al.			
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	AOO	6,008,902	12/28/1999	Rinn			
	APP	5,801,832	9/1/1998	Van Der Brink			
	AQQ	5,781,277	7/14/1998	Iwamoto			
	ARR	5,764,361	6/9/1998	Kato et al.			
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	ATT	5,724,136	3/3/1998	Zanoni			
	AUU	5,663,893	9/2/1997	Wampler et al.			
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	AYY	5,331,400	7/19/1994	Wilkening et al.			
	AZZ	5,187,543	2/16/1993	Ebert			
	AAAA	5,114,234	5/19/1992	Otsuka et al.			
	ABBB	5,064,289	11/12/1991	Bockman			

Examiner Signature	Date Considered
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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ACCC	4,881,816	11/21/1989	Zanoni			
	ADDD	4,859,066	8/22/1989	Sommargren			
	AEEE	4,802,765	2/7/1989	Young et al.			
	AFFF	4,790,651	12/13/1988	Brown et al.			
	AGGG	4,714,339	12/22/1987	Lau et al.			
	AHHH	4,711,573	12/8/1987	Wijntjes et al.			
	AIHH	4,606,638	8/19/1986	Sommargren			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AJJJ	WO 01/90686	11/29/2001	WIPO				
	AKKK	JP 10-260009 Translation of abstract only	9/29/1998	Japan				
	ALLL	JP 7-351078 Abstract only	12/25/1995	Japan				
	AMMM	JP 8-117083 Abstract only	4/15/1996	Japan				

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	ANNN	Bennett, S.J. . "A Double-Passed Michelson Interferometer." Optics Communications, 4:6, pp. 428-430, 1972.
	AOOO	Wu et al. "Analytical modeling of the periodic nonlinearity in heterodyne interferometry." Applied Optics, 37:28, pp. 6696-6700, 1998.
	APPP	Hines et al. "Sub-Nonometer Laser Metrology - Some Techniques and Models. ESO Conference on High-Resolution Imaging by Interferometry II, pp.1195-1204, 1991
	AQQQ	Bobroff, Norman. "Recent advances in displacement measuring interferometry." Meas. Sci. Technol. 4, pp. 907-926, 1993.
	ARRR	Oka et al. "Polarization heterodyne interferometry using another local oscillator beam." Optics Communications, 92, pp. 1-5, 1992.
	ASSS	Badami et al. "Investigation of NonLinearity in High Accuracy Heterodyne Laser Interferometry." American Society for Precision Engineering, 1997 Proceedings, 16, pp. 153-156, 1997.
	ATTT	Bobroff, Norman. "Residual errors in laser interferometry from air turbulence and nonlinearity." Applied Optics, 26:13, pp. 2676-2686, 1987.

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